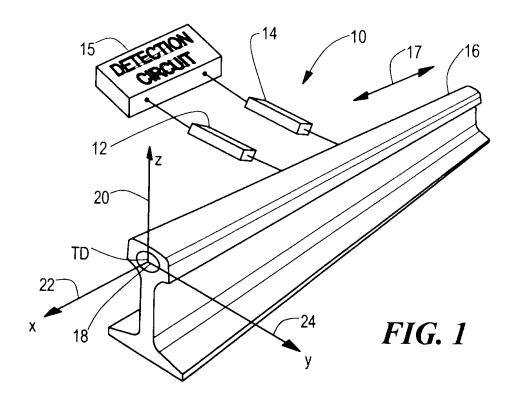
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ney: Handiorio & Teska
Page 1 of 10

1/10



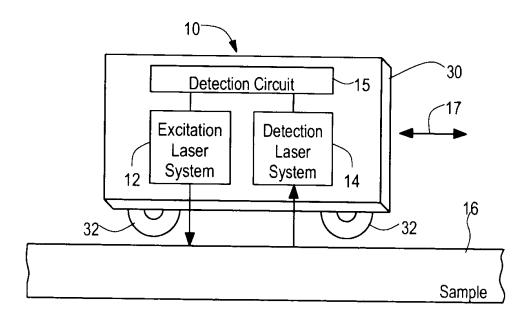


FIG. 2

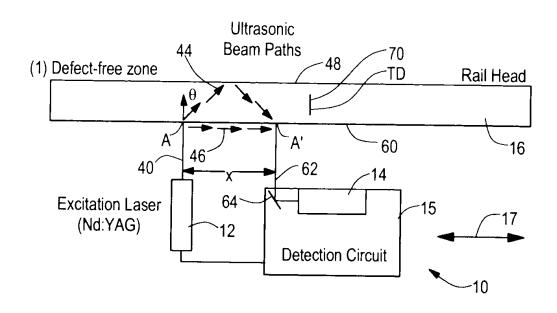


FIG. 3

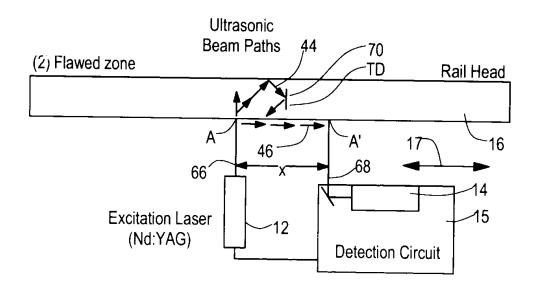


FIG. 4

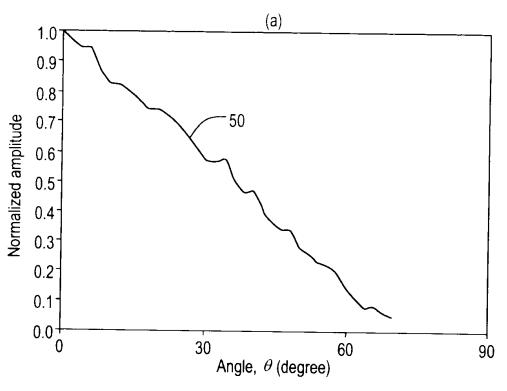


FIG. 5

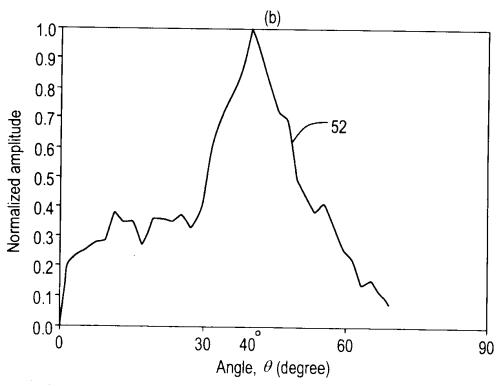
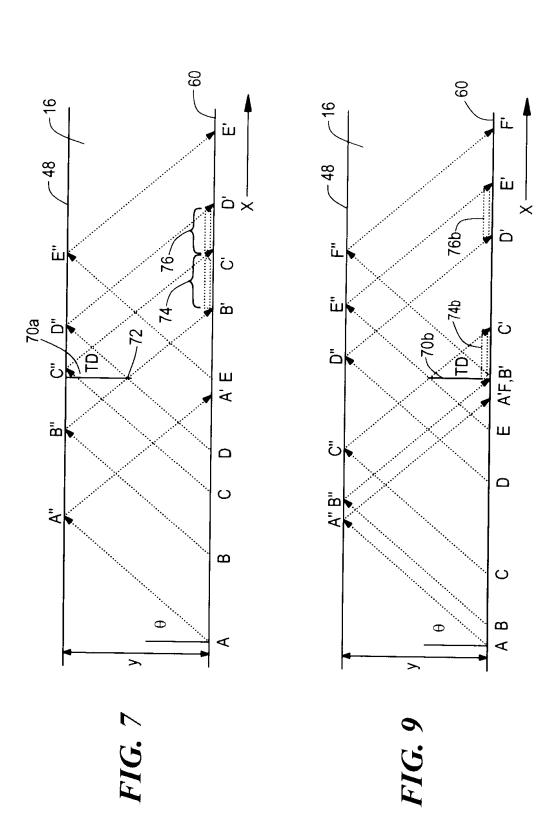


FIG. 6

No.: MIT-114J
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Page 4 of 10

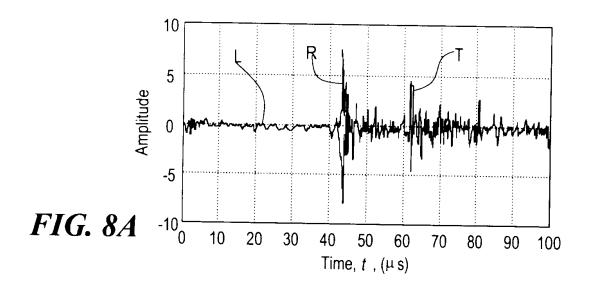
4/10

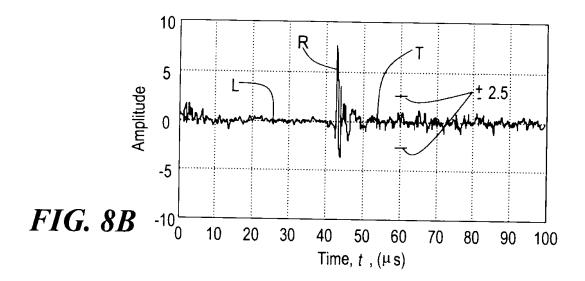


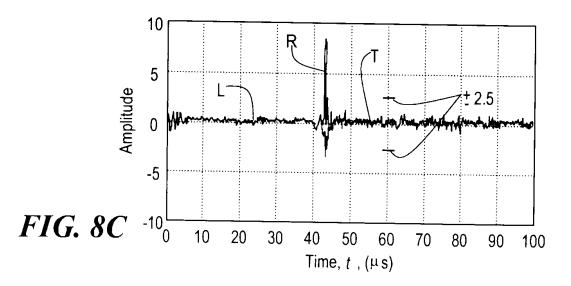
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Page 5 of 10

Iandiorio & Teska





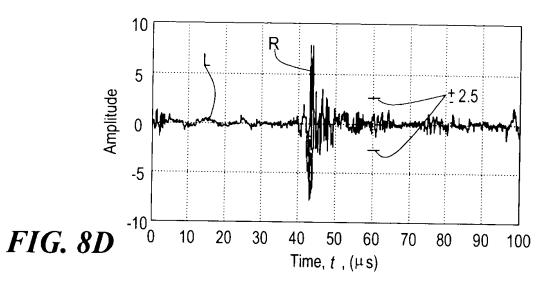


Title: DETECTION SYSTEM AND METHOD

Page 6 of 10

Iandiorio & Teska

6/10



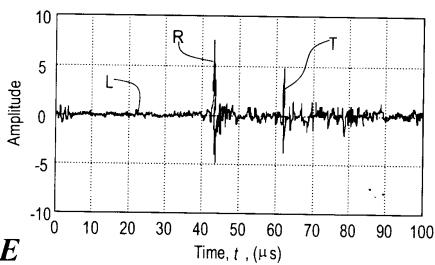
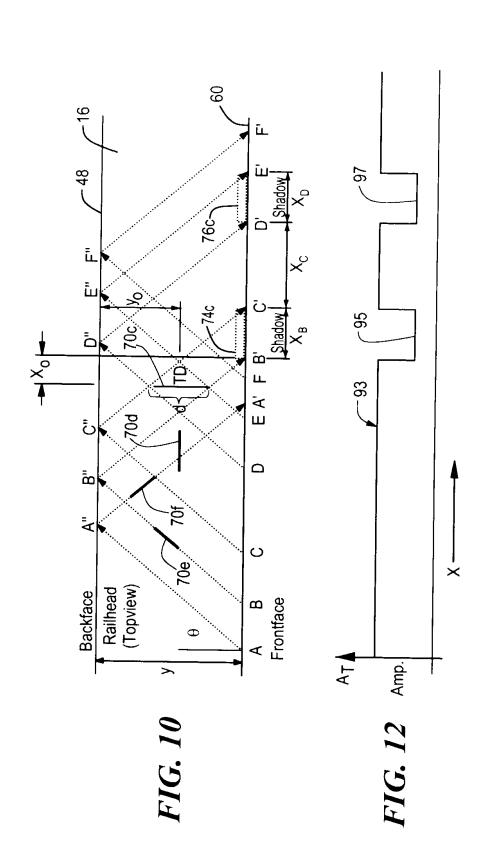


FIG. 8E

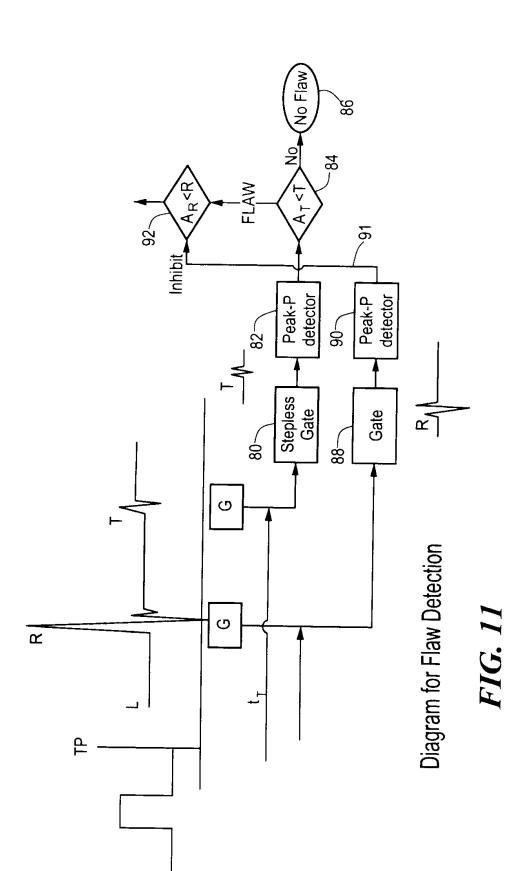
7/10



ey: landiorio & Teska

Page 8 of 10

8/10



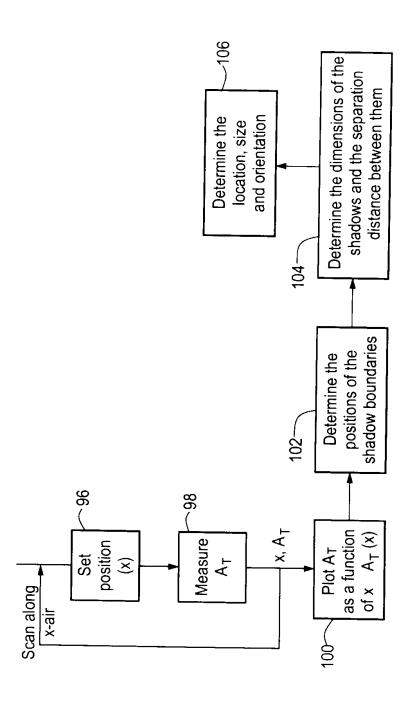
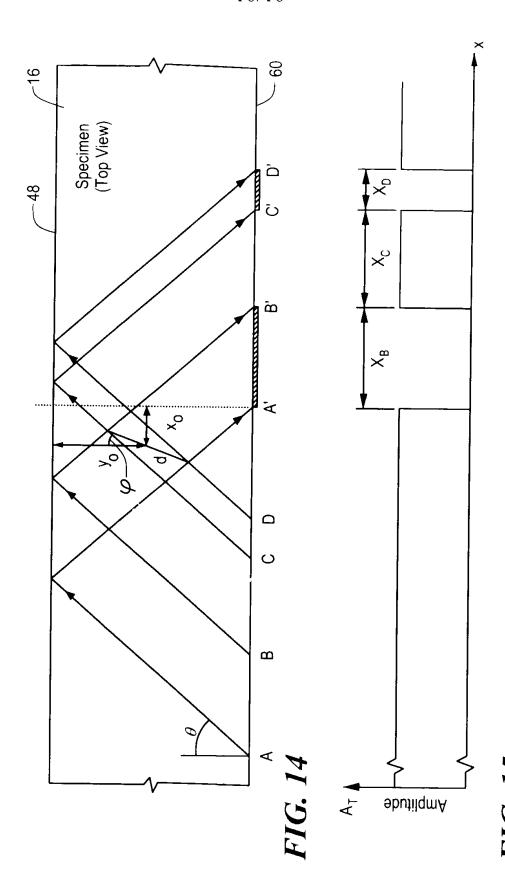


FIG. 13

20 of 10

10/10



F1G. 15